

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10788461	MIZUGAKI ET AL.
	<b>Examiner</b>  Lee, Siu M	<b>Art Unit</b>  2611

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	316, 340, 343,146,350	3/22/2007	Siu M. Lee

### SEARCH NOTES

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EAST	3/20/2007	Siu M. Lee
Discuss the application with Chieh Fan	3/20/2007	Siu M. Lee

### INTERFERENCE SEARCH

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